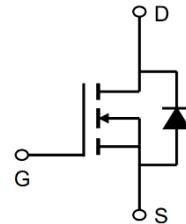


## Description

The AP68N04DF uses advanced **SGT V** technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

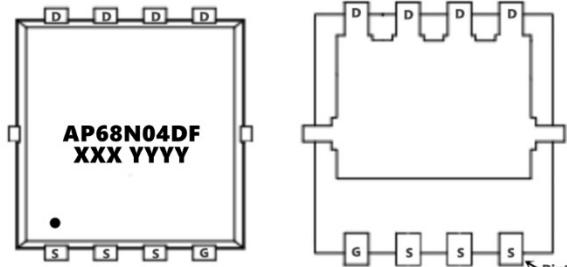


## General Features

$V_{DS} = 40V$   $I_D = 68A$

$R_{DS(ON)} < 8.5m\Omega$  @  $V_{GS}=10V$  (**Type: 6.9mΩ**)

$C_{iss} \approx 690\text{ PF}$

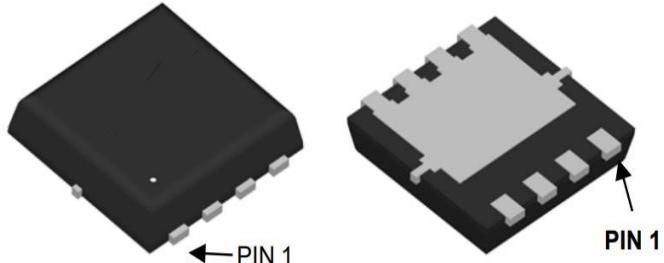


## Application

Wireless charging

Boost driver

Brushless motor



## Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP68N04DF	PDFN3*3-8L	AP68N04DF XXX YYYY	5000

## Absolute Maximum Ratings ( $T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	40	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D@T_A=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	68	A
$I_D@T_A=70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	33	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	125	A
EAS	Single Pulse Avalanche Energy <sup>3</sup>	31	mJ
$I_{AS}$	Avalanche Current	31	A
$P_D@T_A=25^\circ C$	Total Power Dissipation <sup>4</sup>	1.67	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-Ambient <sup>1</sup>	85	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	30	°C/W



**40V N-Channel Enhancement Mode MOSFET**
**N-Channel Electrical Characteristics ( $T_J=25^\circ\text{C}$ , unless otherwise noted)**

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$ , $I_D=250\mu\text{A}$	40	47	---	V
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10\text{V}$ , $I_D=12\text{A}$	---	6.9	8.5	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$ , $I_D=10\text{A}$	---	10.5	15	
VGS(th)	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250\mu\text{A}$	1.2	1.6	2.5	V
IDSS	Drain-Source Leakage Current	$V_{DS}=32\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=25^\circ\text{C}$	---	---	1	$\text{uA}$
		$V_{DS}=32\text{V}$ , $V_{GS}=0\text{V}$ , $T_J=55^\circ\text{C}$	---	---	5	
IGSS	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$ , $V_{DS}=0\text{V}$	---	---	$\pm 100$	nA
R <sub>g</sub>	Gate Resistance	$V_{DS}=0\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	1.7	---	$\Omega$
Q <sub>g</sub>	Total Gate Charge (4.5V)	$V_{DS}=20\text{V}$ , $V_{GS}=4.5\text{V}$ , $I_D=12\text{A}$	---	5.8	---	nC
Q <sub>gs</sub>	Gate-Source Charge		---	3	---	
Q <sub>gd</sub>	Gate-Drain Charge		---	1.2	---	
T <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD}=15\text{V}$ , $V_{GS}=10\text{V}$ , $R_G=3.3\Omega$ $I_D=1\text{A}$	---	14.3	---	ns
T <sub>r</sub>	Rise Time		---	5.6	---	
T <sub>d(off)</sub>	Turn-Off Delay Time		---	20	---	
T <sub>f</sub>	Fall Time		---	11	---	
C <sub>iss</sub>	Input Capacitance	$V_{DS}=15\text{V}$ , $V_{GS}=0\text{V}$ , $f=1\text{MHz}$	---	690	---	pF
C <sub>oss</sub>	Output Capacitance		---	193	---	
C <sub>rss</sub>	Reverse Transfer Capacitance		---	38	---	
I <sub>S</sub>	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0\text{V}$ , Force Current	---	---	30	A
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	$V_{GS}=0\text{V}$ , $I_S=1\text{A}$ , $T_J=25^\circ\text{C}$	---	---	1	V

**Note :**

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
- 3、The EAS data shows Max. rating . The test condition is  $VDD =32\text{V}$ , $VGS =10\text{V}$ , $L=0.1\text{mH}$ , $IAS =31\text{A}$
- 4、The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
- 5、The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub> , in real applications , should be limited by total power dissipation.

**Typical Characteristics**

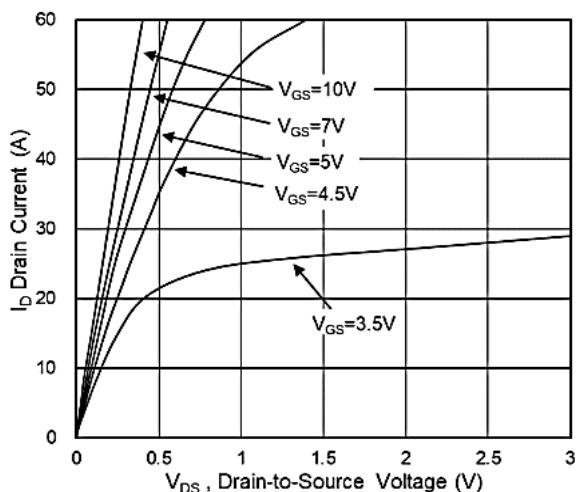


Fig.1 Typical Output Characteristics

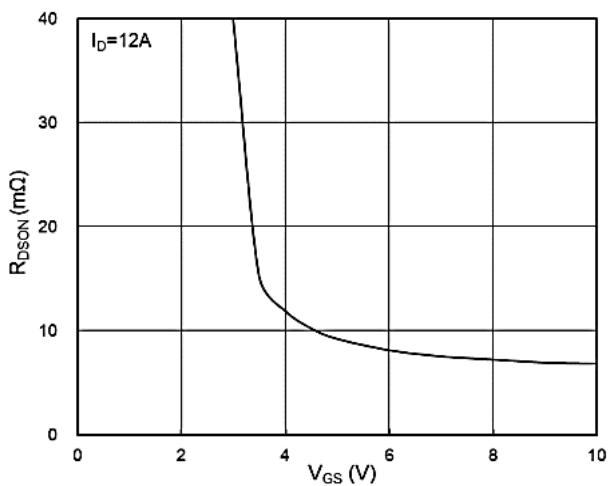


Fig.2 On-Resistance vs G-S Voltage

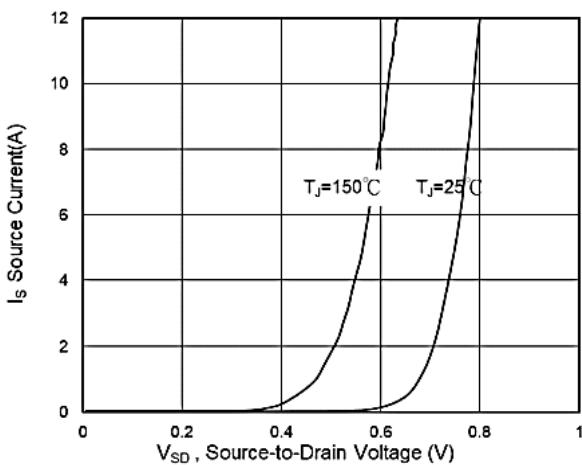


Fig.3 Source Drain Forward Characteristics

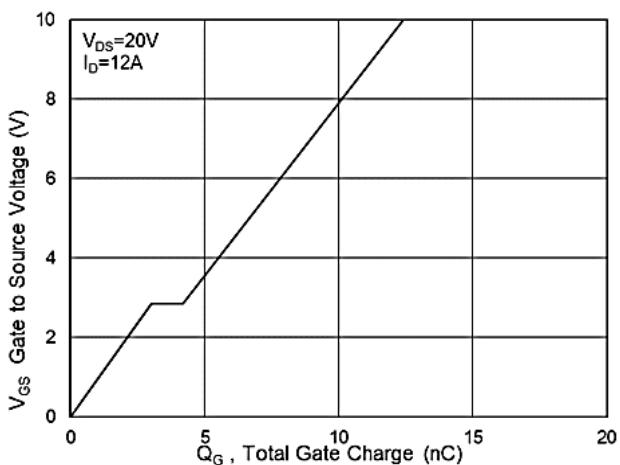


Fig.4 Gate-Charge Characteristics

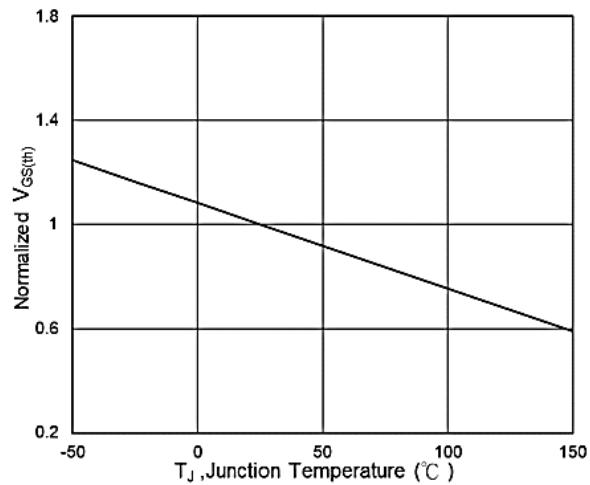


Fig.5 Normalized  $V_{GS(th)}$  vs  $T_J$

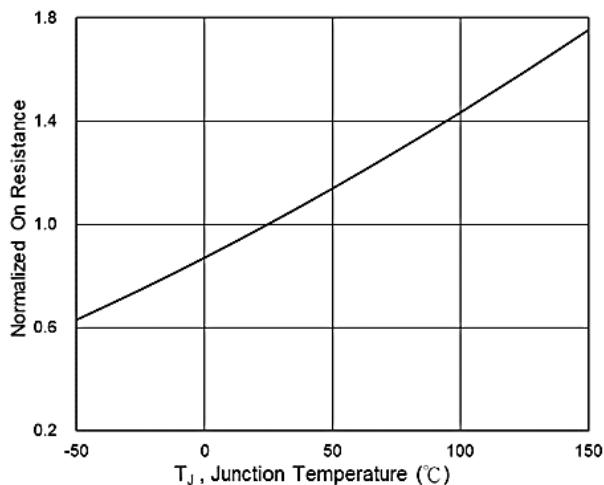
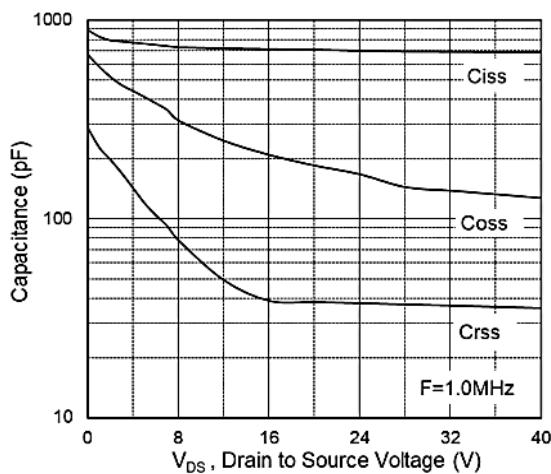
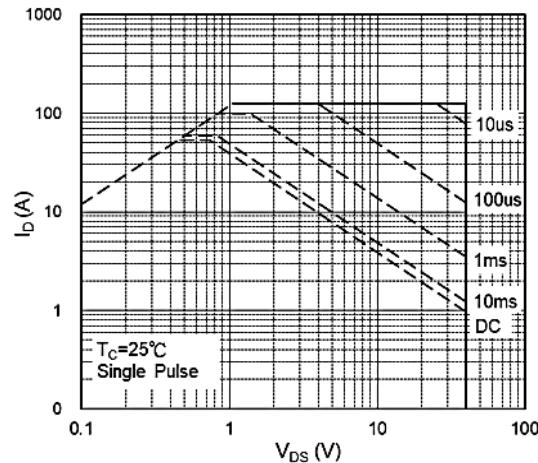
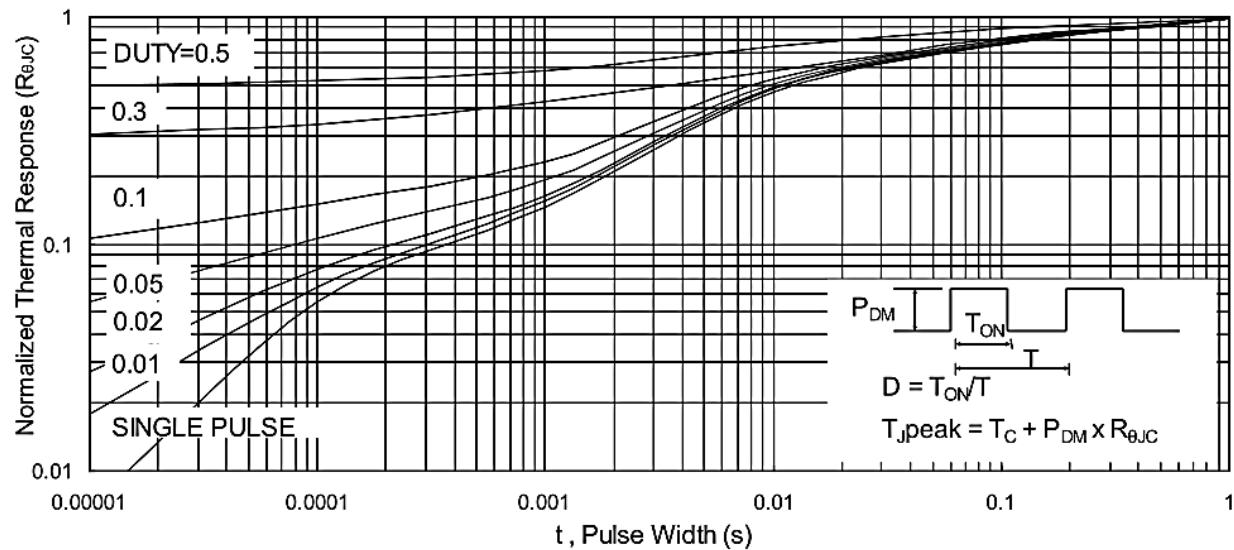
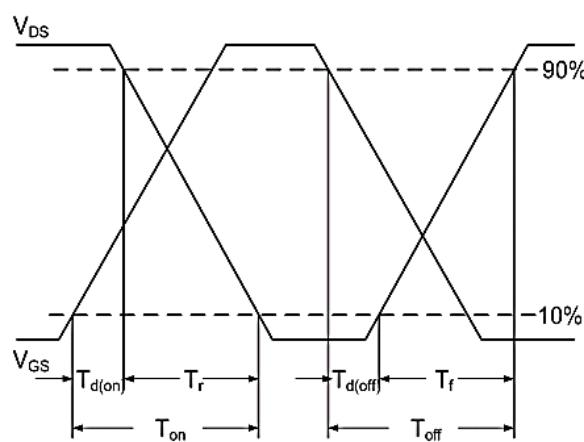
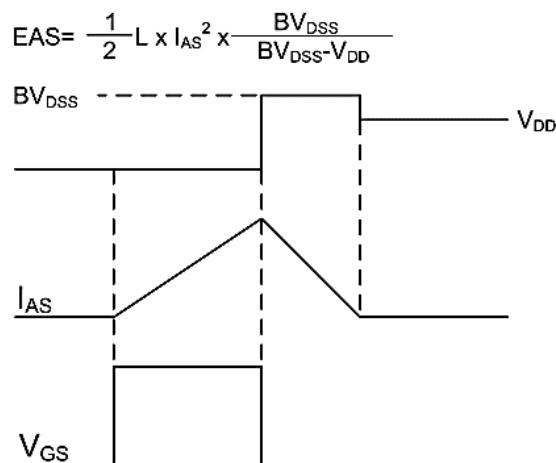
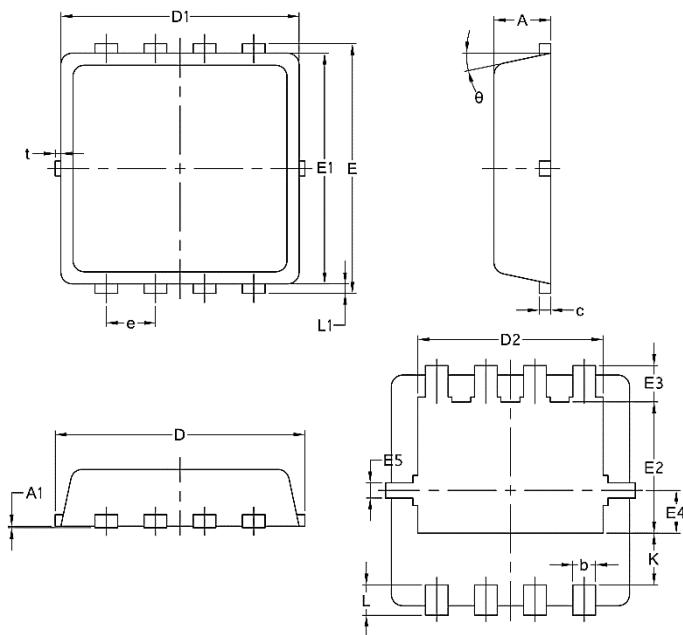


Fig.6 Normalized  $R_{DS(on)}$  vs  $T_J$

**40V N-Channel Enhancement Mode MOSFET**

**Fig.7 Capacitance**

**Fig.8 Safe Operating Area**

**Fig.9 Normalized Maximum Transient Thermal Impedance**

**Fig.10 Switching Time Waveform**

**Fig.11 Unclamped Inductive Waveform**

**Package Mechanical Data-PDFN3\*3-8L-JQ Single**


Symbol	Common		
	mm	mm	mm
	Mim	Nom	Max
A	0.70	0.75	0.85
A1	/	/	0.05
b	0.20	0.30	0.40
c	0.10	0.152	0.25
D	3.15	3.30	3.45
D1	3.00	3.15	3.25
D2	2.29	2.45	2.65
E	3.15	3.30	3.45
E1	2.90	3.05	3.20
E2	1.54	1.74	1.94
E3	0.28	0.48	0.65
E4	0.37	0.57	0.77
E5	0.10	0.20	0.30
e	0.60	0.65	0.70
K	0.59	0.69	0.89
L	0.30	0.40	0.50
L1	0.06	0.125	0.20
t	0	0.075	0.13
Φ	10	12	14